



# AO4405

## 30V P-Channel MOSFET

### General Description

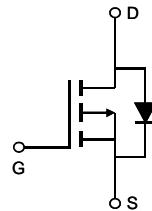
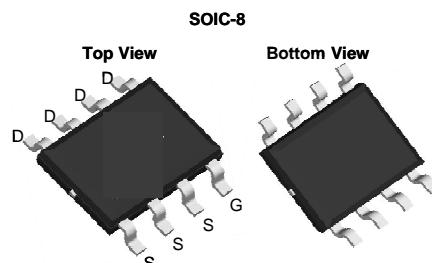
The AO4405 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use as a load switch or in PWM applications.

### Product Summary

$V_{DS}$	-30V
$I_D$ (at $V_{GS}=-10V$ )	-6A
$R_{DS(ON)}$ (at $V_{GS}=-10V$ )	< 50mΩ
$R_{DS(ON)}$ (at $V_{GS} = -4.5V$ )	< 85mΩ

100% UIS Tested

100%  $R_g$  Tested



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$I_D$	-6	A
Current $T_A=70^\circ\text{C}$		-5.1	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-30	
Avalanche Current <sup>C</sup>	$I_{AS}, I_{AR}$	17	A
Avalanche energy $L=0.1\text{mH}$ <sup>C</sup>	$E_{AS}, E_{AR}$	14	mJ
Power Dissipation <sup>B</sup>	$P_D$	3.1	W
$T_A=70^\circ\text{C}$		2	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \le 10\text{s}$	$R_{\theta JA}$	31	40	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		59	75	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	16	24	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 20\text{V}$			$\pm 100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.4	-1.9	-2.4	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-30			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-6\text{A}$ $T_J=125^\circ\text{C}$	33	50		$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-4\text{A}$	50	70		
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-6\text{A}$	53	85		$\text{m}\Omega$
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$	-0.8	-1		V
$I_S$	Maximum Body-Diode Continuous Current				-3.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		520		pF
$C_{\text{oss}}$	Output Capacitance			100		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			65		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	3.5	7.5	11.5	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-6\text{A}$		9.2	11	nC
$Q_g(4.5\text{V})$	Total Gate Charge			4.6	6	nC
$Q_{\text{gs}}$	Gate Source Charge			1.6		nC
$Q_{\text{gd}}$	Gate Drain Charge			2.2		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=2.5\Omega, R_{\text{GEN}}=3\Omega$		7.5		ns
$t_r$	Turn-On Rise Time			5.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			19		ns
$t_f$	Turn-Off Fall Time			7		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		11		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		5.3		nC

A. The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{QJL}}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

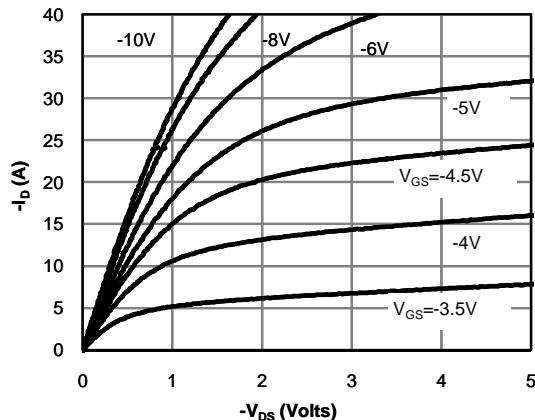


Fig 1: On-Region Characteristics (Note E)

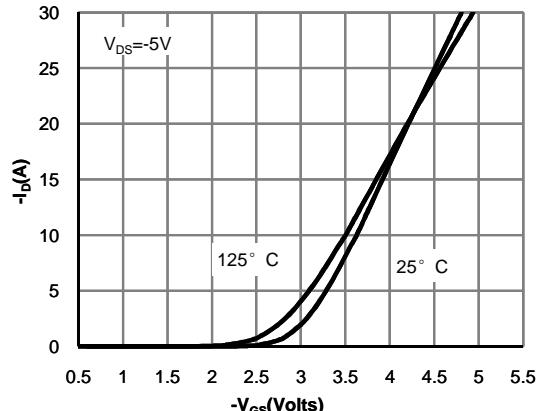


Figure 2: Transfer Characteristics (Note E)

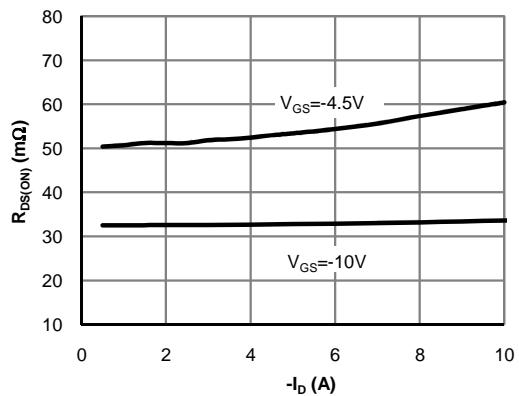


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

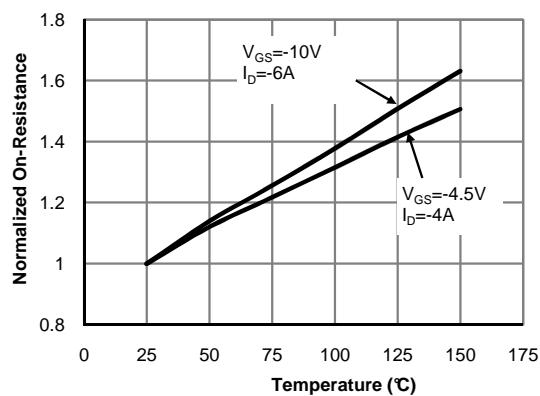


Figure 4: On-Resistance vs. Junction Temperature (Note E)

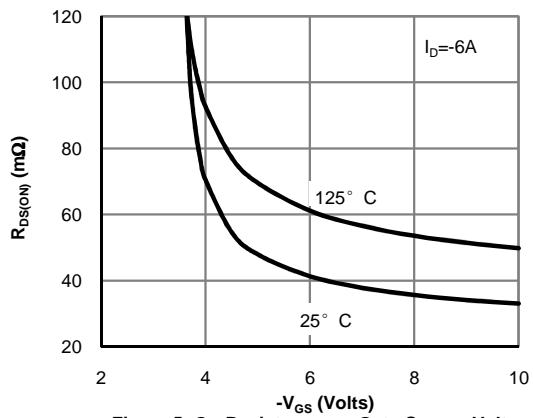


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

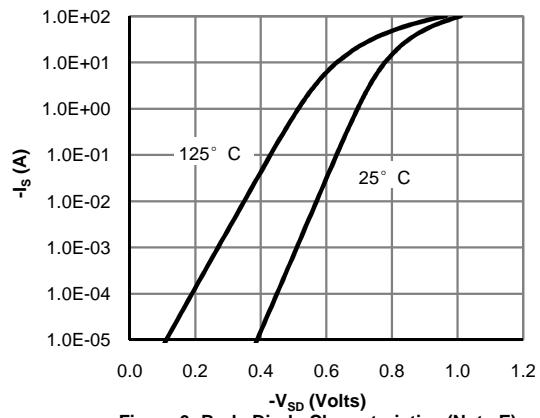


Figure 6: Body-Diode Characteristics (Note E)

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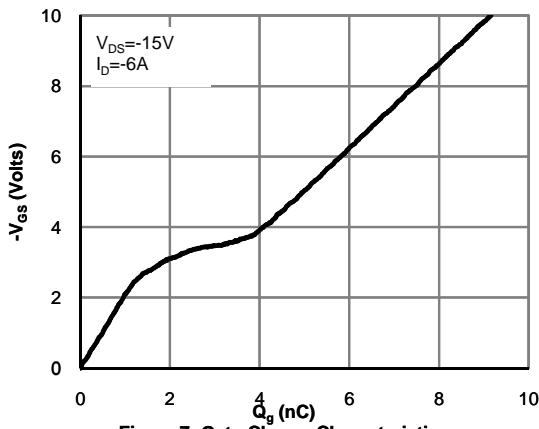


Figure 7: Gate-Charge Characteristics

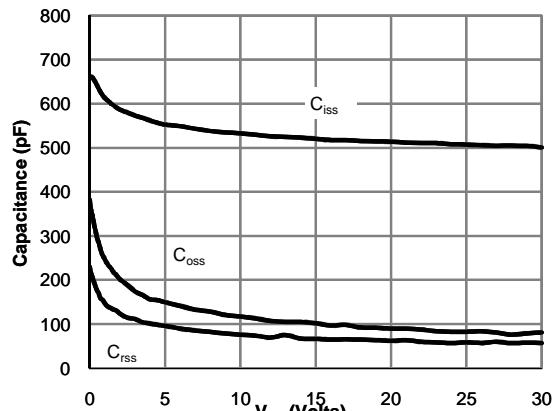


Figure 8: Capacitance Characteristics

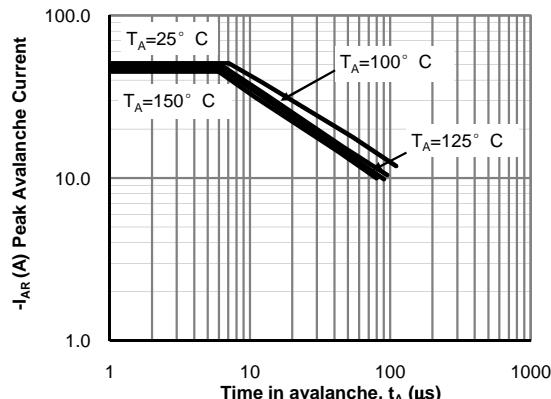


Figure 9: Single Pulse Avalanche capability (Note C)

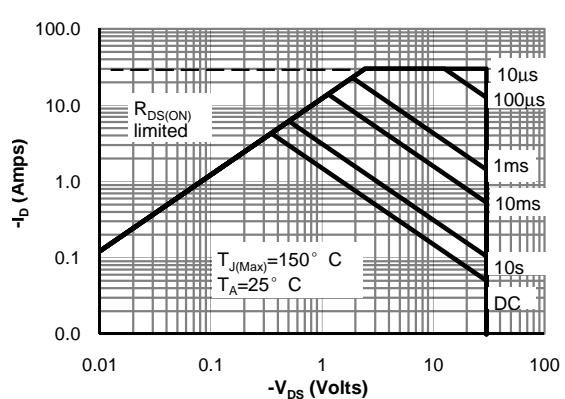


Figure 10: Maximum Forward Biased Safe Operating Area (Note F)

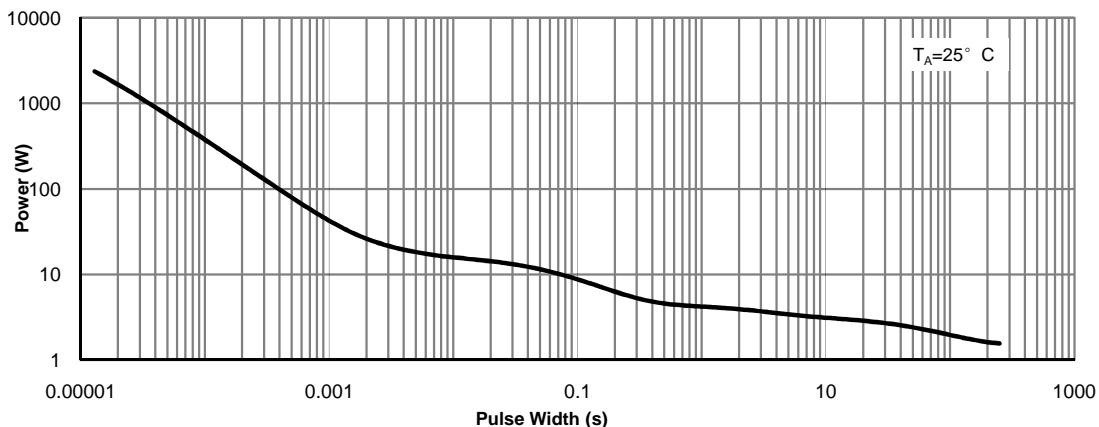


Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note F)

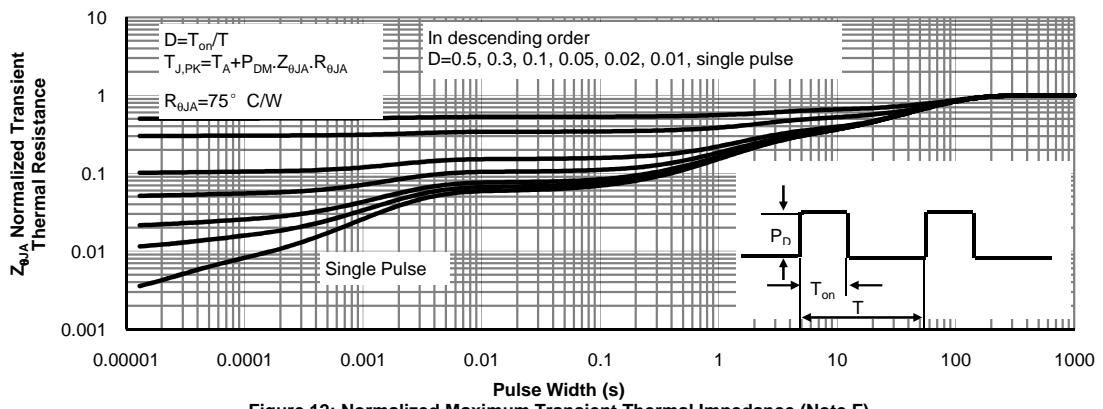
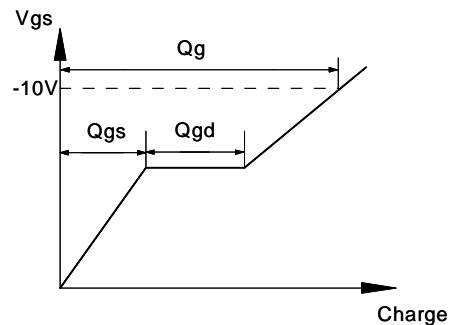
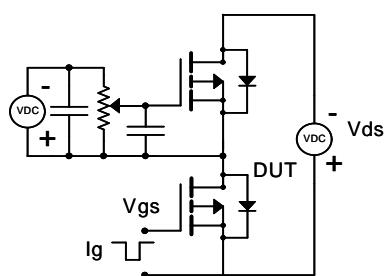
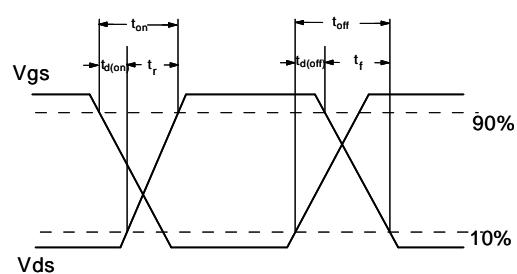
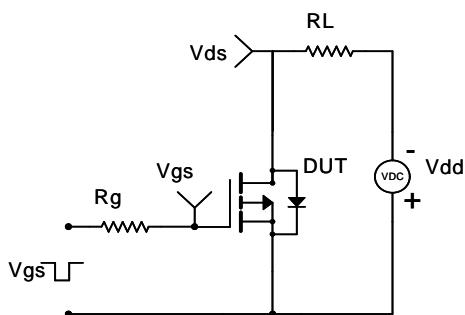
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

Figure 12: Normalized Maximum Transient Thermal Impedance (Note F)

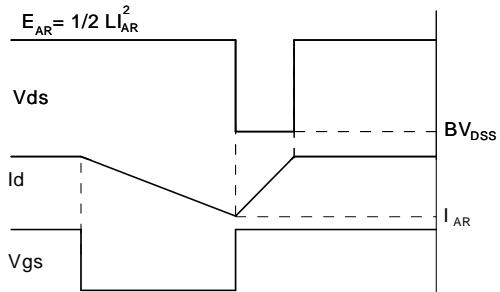
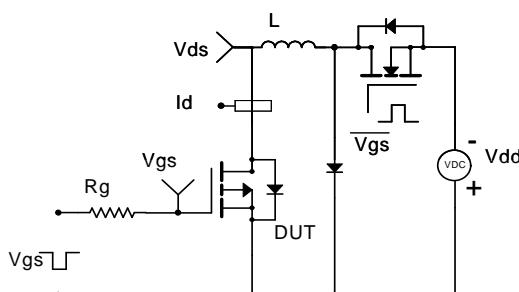
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



### Diode Recovery Test Circuit & Waveforms

